# **GF28: I<sup>2</sup>C**



#### Libraries

Name	Process	Form Factor
RGO GF28 50V50 SLP 25C I2C	SLP	Staggered

## Summary

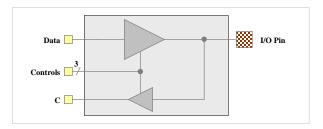
Conforms to UM10204 I2C-bus specification and user manual, Rev.4 - 13 February 2012, NXP

The I2C I/O pad is an open-drain bi-directional I/O cell that is designed for the I2C two-line interface. Utilized with the 3.3V GPIO library, it is compliant with the I2C-bus specification.

The I2C cell is designed for 100Kbps and 400 Kbps operation.

An open-drain design, this cell requires an external pull-up resistor to a high voltage power supply. The pull-up power supply (VDDP) for this design is between 4.50V to 5.50V. It is independent of the I/O cell power supply (DVDD). The sizing of the external resistor is application dependent and can range from 1.7  $K\Omega$  to 40  $K\Omega$ .

## I2P\_ON\_003\_5T\_NC



## **Recommended operating conditions**

	Description	Min	Nom	Max	Units
$V_{DVDD}$	I/O supply voltage	2.70	3.3	3.63	V
$V_{VDDP}$	External pull-up supply to PAD	2.70	3.3	3.63	V
$V_{VDD}$	Core supply voltage	0.90	1.0	1.10	V
		0.99	1.1	1.155	V
TJ	Junction temperature	-40	25	125	°C
$V_{PAD}$	Voltage at PAD	$V_{\text{DVSS}} - 0.3$	-	$V_{VDDP}$	V

## **Product Features**

- Supported I2C operating modes:
  - Standard-mode (Sm) 100 Kbps data rate
  - o Fast mode (Fm) 400 Kbps data rate
- Open drain operation only (floating NWELL with PMOS used for ESD protection only)
- Built-in output slew rate control to meet I<sup>2</sup>C T<sub>of</sub> minimum of (20 x VDDP/5.5V) ns
- Output enable
- Receiver enable
- ESD protection uses snap-back devices (no diode to the positive power supply)
- Standard LVCMOS input thresholds with Schmidt trigger (hysteresis) option
- Staggered I/O CUP implementation
- Power-on sequencing independent design with Power-On Control
- DVDD = 2.97V to 3.63V and VDD = 0.90V to 1.155V
- Pad VDDP (power supply reference for Output) = 4.50V to 5.50V independent of DVDD.
- The circuit consumes no DC supply current in the static state

## **ESD Protection:**

- JEDEC compliant
  - o 2KV ESD Human Body Model (HBM)
  - o 200V ESD Machine Model (MM)
  - o 500V ESD Charge Device Model (CDM)

# Latch-up Immunity:

- JEDEC compliant
  - o Tested to I-Test criteria of ± 100mA @ 125°C

## **Characterization Corners**

Nominal VDD	Model	VDD	DVDD = 3.3V	Temperature
	FF	+5%	+10%	-40°C
	FF	+5%	+10%	125°C
1.1	TT	nominal	nominal	25°C
	SS	-10%	-10%	-40°C
	SS	-10%	-10%	125°C
	FF	+10%	+10%	-40°C
	FF	+10%	+10%	125°C
1.0	TT	nominal	nominal	25°C
	SS	-10%	-10%	-40°C
	SS	-10%	-10%	125°C



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Published by:

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Printed in the United States of America